

## APPLICATION DATA SHEET

### APPLICATION INFORMATION

Application Type:: REGULAR  
Subject Matter:: UTILITY  
CD-ROM or CD-R?: NONE  
Title:: SEMICONDUCTOR WAFER  
INSPECTING METHOD  
Attorney Docket Number:: 240626US2  
Total Drawing Sheets:: 13

### INVENTOR INFORMATION

Applicant Authority Type:: INVENTOR  
Primary Citizenship Country:: Japan  
Status:: FULL CAPACITY  
Given Name:: Hideki  
Family Name:: NARUOKA  
City of Residence:: Tokyo  
Country of Residence:: Japan  
Street of Mailing Address:: c/o Renesas Technology Corp., 4-1,  
Marunouchi 2-chome, Chiyoda-ku,  
City of Mailing Address:: Tokyo  
Country of Mailing Address:: Japan

### CORRESPONDENCE INFORMATION

Correspondence Customer Number:: 22850

### REPRESENTATIVE INFORMATION

Representative Customer Number:: 22850

### FOREIGN PRIORITY INFORMATION

Application Number:	Country::	Filing Date::	Priority Claimed::
2002-293613	Japan	10/07/02	YES

### ASSIGNMENT INFORMATION

Assignee Name:: Renesas Technology Corp.

Street of Mailing Address::	4-1, Marunouchi 2-chome,
City of Mailing Address::	Chiyoda-ku,
Country of Mailing Address::	Tokyo
	Japan